

Shubnikov–de Haas Oscillations of High-Mobility Holes in Monolayer and Bilayer WSe₂: Landau Level Degeneracy, Effective Mass, and Negative Compressibility

Babak Fallahazad,¹ Hema C. P. Movva,¹ Kyoungwan Kim,¹ Stefano Larentis,¹ Takashi Taniguchi,² Kenji Watanabe,² Sanjay K. Banerjee,¹ and Emanuel Tutuc^{1,*}

¹*Department of Electrical and Computer Engineering, Microelectronics Research Center, The University of Texas at Austin, Austin, Texas 78758, USA*

²*National Institute of Materials Science, 1-1 Namiki Tsukuba, Ibaraki 305-0044, Japan*

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We study the magnetotransport properties of high-mobility holes in monolayer and bilayer WSe₂, which display well defined Shubnikov–de Haas (SdH) oscillations, and quantum Hall states in high magnetic fields. In both mono- and bilayer WSe₂, the SdH oscillations and the quantum Hall states occur predominantly at even filling factors, evincing a twofold Landau level degeneracy. The Fourier transform analysis of the SdH oscillations in bilayer WSe₂ reveals the presence of two subbands localized in the top or the bottom layer, as well as negative compressibility. From the temperature dependence of the SdH oscillations we determine a hole effective mass of $0.45m_0$ for both mono- and bilayer WSe₂.

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Molybdenum and tungsten-based transition metal dichalcogenides (TMDs) in the *2H* phase are characterized by a honeycomb lattice similar to graphene. The conduction and valence band minima in monolayer TMDs are reached at the corners (*K* points) of the first Brillouin zone, and away from the band minima the broken inversion symmetry combined with the strong spin-orbit coupling lifts the fourfold (spin-valley) degeneracy, and yields coupled spin and valley degrees of freedom [1]. The spin-valley coupling present in TMDs has been probed extensively using optical excitation, thanks to peculiar selection rules [1–5]. In perpendicular magnetic fields the spin-valley coupling translates into twofold degenerate Landau levels (LLs) in TMDs [6,7], as opposed to the case of graphene where single particle states in LLs are fourfold degenerate [8,9]. Exploring the TMD electron physics at low temperatures and high magnetic fields has proven more arduous because of the moderate mobility, combined with the high resistance of metal-TMD contacts at reduced temperatures. Attempts to address this issue include using contacts such as graphene on MoS₂ [10], or Pt underneath WSe₂ [11]. To reduce the surface roughness and charged impurity scattering in ultrathin TMDs, atomically flat dielectrics such as hexagonal boron-nitride (hBN) are preferable [12].

Here we present a magnetotransport study of dual-gated mono- and bilayer WSe₂ with top and bottom hBN gate dielectrics, and bottom Pt contacts. Both mono- and bilayer WSe₂ samples exhibit Shubnikov–de Haas (SdH) oscillations in perpendicular magnetic fields with a density-to-frequency ratio of $2e/h$, indicating a twofold LL degeneracy; e is the electron charge, and h Planck’s constant. In bilayer WSe₂, we observe quantum Hall states (QHSs) at even filling factors $\nu = 6, 8, 10, \dots$, which

further confirm the twofold degenerate LLs. At the highest magnetic field we observe a $\nu = 5$ QHS which signals a full lifting of the LL degeneracy. The Fourier transform (FT) analysis on the SdH oscillations in bilayer WSe₂ reveals the presence of two subbands, each localized in the top or the bottom layer, as well as negative compressibility. Using the SdH temperature dependence we determine an effective hole mass in mono- and bilayer WSe₂ of $m^* = 0.45m_0$, where m_0 is the bare electron mass.

Figure 1(a) shows an optical micrograph of a dual-gated WSe₂ Hall bar sample encapsulated by hBN dielectrics, and fabricated using a layer pickup method similar to Ref. [11]. The samples use synthetic WSe₂ (HQGraphene, CAS No. 12067-46-8) mechanically exfoliated on SiO₂/Si substrates. Using a combination of optical contrast, Raman spectroscopy, and photoluminescence (PL) spectroscopy, mono- and bilayer WSe₂ flakes are identified. Thanks to the thickness dependence of the band structure, mono- and bilayer WSe₂ possess distinct PL signatures that unambiguously differentiate them from thicker WSe₂ [13–15]. Figure 1(b) shows sample PL spectra of mono- and bilayer WSe₂ as exfoliated, measured at an incident excitation wavelength of 532 nm. Monolayer WSe₂ shows a single peak at 1.65 eV, consistent with a direct energy gap, and in good agreement with previously reported energy gap values [13,15]. Bilayer WSe₂ shows a broader peak that can be fitted with two Lorentzian peaks centered at 1.55 and 1.61 eV, reflecting the transition to indirect energy gap [13,15,16]. The WSe₂ flakes were also investigated using Raman spectroscopy, where a distinct difference between the spectra of mono- and bilayer WSe₂ is the presence of the A_{1g}^2 mode at 310 cm⁻¹ [13]. Using mechanically exfoliated hBN flakes combined with micromanipulation and transfer techniques, dual-gated WSe₂ samples

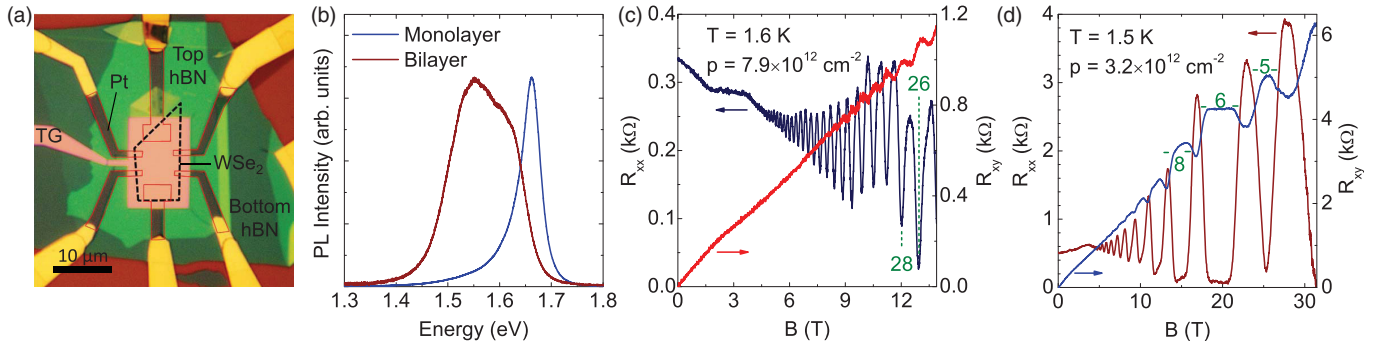


FIG. 1. (a) Optical micrograph of a dual-gated WSe₂ sample with bottom Pt contacts. The dashed black (red) contour marks the boundaries of the WSe₂ flake (Pt contacts). (b) PL spectra of mono- and bilayer WSe₂ normalized to the highest intensity. (c) Monolayer WSe₂ R_{xx} (left axis) and R_{xy} (right axis) vs B measured at $T = 1.6$ K, at a hole density $p = 7.9 \times 10^{12} \text{ cm}^{-2}$. The two lowest filling factors $\nu = 26$ and $\nu = 28$ are indicated. (d) Bilayer WSe₂ R_{xx} (left axis) and R_{xy} (right axis) vs B measured at $T = 1.5$ K, and at $p = 3.2 \times 10^{12} \text{ cm}^{-2}$. A quantized R_{xy} plateau is observed at $\nu = 6$.

encapsulated in hBN dielectrics, and with bottom Pt contacts [11] are fabricated. Four dual-gated WSe₂ samples, two monolayers, and two bilayers were investigated in this study, all with consistent results. Here we focus on data from two samples, one monolayer WSe₂, and one bilayer WSe₂. The samples are characterized using small signal, low frequency lock-in techniques, at temperatures down to $T = 1.5$ K, and perpendicular magnetic fields up to $B = 31.5$ T.

Examples of longitudinal (R_{xx}) and Hall (R_{xy}) resistance measured as a function of the B field at fixed carrier densities for mono- and bilayer WSe₂ are shown in Figs. 1(c) and 1(d), respectively. The R_{xx} vs B data of Fig. 1(c), measured at $T = 1.6$ K, top-gate voltage $V_{TG} = -6$ V, and back-gate voltage $V_{BG} = 0$ V show well-defined SdH oscillations starting at $B \cong 4.5$ T. The filling factors corresponding to the two lowest LLs probed in this measurement, $\nu = 26$ and $\nu = 28$, are marked. The hole density (p) calculated from the slope of R_{xy} vs B at low fields is $p = 7.9 \times 10^{12} \text{ cm}^{-2}$.

The bilayer WSe₂ magnetotransport data of Fig. 1(d) are measured at $T = 1.5$ K, $V_{TG} = -6.4$ V, and $V_{BG} = 60$ V.

The hole density is $p = 3.2 \times 10^{12} \text{ cm}^{-2}$. Similar to the monolayer WSe₂ case, the SdH oscillations are present in bilayer WSe₂, along with developing QHSs at even filling factors. The data show developed QHSs accompanied by R_{xy} plateaux at $\nu = 6$ and $\nu = 8$, along with an onset of the $\nu = 4$ QHS at B fields larger than 31 T. Furthermore, a developing QHS at $\nu = 5$ signals a full lifting of the LL degeneracy. The data of Figs. 1(c) and 1(d) combined suggest the oscillations predominantly occur at even filling factors in both mono- and bilayer WSe₂.

Figure 2(a) shows R_{xx} and R_{xy} vs B data measured in monolayer WSe₂ at different V_{TG} values, $V_{BG} = 0$ V, and $T = 1.6$ K. Figure 2(b) shows the FT amplitude vs frequency corresponding to the R_{xx} vs B^{-1} of Fig. 2(a). The FT is calculated by first subtracting a third order polynomial from the R_{xx} vs B^{-1} data to center the oscillations around zero, multiplying the data by a Hamming window, and finally applying a fast Fourier transform algorithm. The FT data reveal a principal peak at a frequency (f), along a smaller amplitude second harmonic ($2f$). The f value increases with $|V_{TG}|$, and therefore with increasing the hole density. For a 2D carrier system the

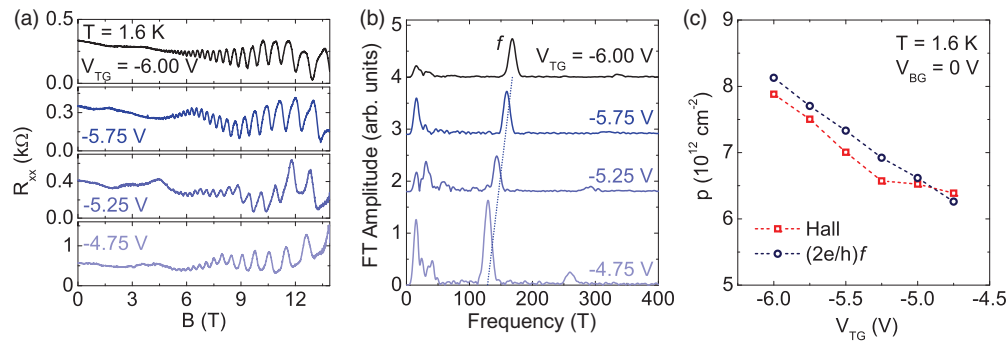


FIG. 2. (a) R_{xx} vs B measured in monolayer WSe₂ at different V_{TG} values, $V_{BG} = 0$ V, and $T = 1.6$ K. (b) FT amplitude vs frequency corresponding to R_{xx} vs B^{-1} data of panel (a); the traces are shifted for clarity. The dashed line is a guide to the eye. (c) p vs V_{TG} of monolayer WSe₂ measured at $V_{BG} = 0$ V and $T = 1.6$ K. The red symbols (rectangles) represent the Hall density, and the blue symbols (circles) show $p = (2e/h)f$. The agreement confirms the twofold LL degeneracy.

SdH frequency-density dependence is $f = (1/g)(h/e)p$, where g is the LL degeneracy. For example, $g = 1$ ($g = 2$) for spin resolved (degenerate) LLs, or $g = 4$ for spin and valley degenerate LLs, as in the case for Si [17], AlAs [18], and graphene 2D systems [8,9]. To determine the LL degeneracy factor in monolayer WSe₂, we examine the ratio of f to the carrier density determined from Hall measurements. Figure 2(c) shows p vs V_{TG} measured at $V_{\text{BG}} = 0$ V, and $T = 1.6$ K in monolayer WSe₂. The carrier density values determined from the FT analysis using $p = (2e/h)f$ are included for comparison, and the agreement confirms the $g = 2$ LL degeneracy.

Figure 3(a) shows R_{xx} vs B measured in bilayer WSe₂ at different V_{BG} values, $V_{\text{TG}} = -6.5$ V, and $T = 1.6$ K. The data show SdH oscillations with a beating pattern at negative V_{BG} . Figure 3(b) shows FT of R_{xx} vs B^{-1} of Fig. 3(a) data at different V_{BG} values. The FT data at positive V_{BG} possess a main peak at a frequency f along with its second harmonic ($2f$) consistent with the monolayer WSe₂ Fig. 2(b) data. Figure 3(b) data show that at $V_{\text{BG}} = -40$ V an additional peak emerges at a lower frequency (f'). The additional peak (f') is absent in monolayer WSe₂. Figure 3(c) summarizes the f and f' frequency values vs V_{BG} in bilayer WSe₂ at two different V_{TG} values, and at $T = 1.6$ K. There are several noteworthy features of Fig. 3(c) data. First, both f and f' have a linear dependence on V_{BG} , albeit in different ranges, positive (negative) V_{BG} for f (f'). Second, the emergence of the additional peak (f') at negative V_{BG} coincides with f becoming weakly dependent on V_{BG} . Third, at a fixed V_{BG} the value of f increases with $|V_{\text{TG}}|$, suggesting that f responds to the carrier density induced by the top gate. When present, f' is insensitive to V_{TG} , but depends linearly on V_{BG} , suggesting that f' responds to the carrier density induced by the back gate. The combined V_{BG} and V_{TG} dependence suggests the peak at frequency f is determined by the hole density induced in the top layer, while the peak at f' is associated with the hole density in the bottom layer

of the bilayer WSe₂. At $V_{\text{BG}} > 0$ V, the bottom layer in bilayer WSe₂ is fully depleted, while the top layer is populated by the applied V_{TG} . A negative V_{BG} populates the bottom layer. When both layers are populated the f and f' frequencies respond largely to the applied V_{TG} and V_{BG} , respectively, and are insensitive to the opposite gate thanks to screening. To verify the above interpretation, Fig. 3(d) shows a comparison of p vs V_{BG} determined from Hall measurements, and from the SdH oscillations, namely $p = (2e/h)(f + f')$. The agreement confirms that f and f' are determined by the top and bottom layer densities, respectively.

The data in Figs. 3(c) and 3(d) are similar to the layer density dependence on gate bias in GaAs double quantum wells separated by a tunneling barrier [19]. Moreover, a peculiar feature of the data in Figs. 3(c) and 3(d) is that the frequency f , and therefore the top layer density, decreases with increasing the total density once the bottom layer becomes populated, signaling negative compressibility for the holes in the bottom WSe₂ layer as a result of interaction. Similar observations have been reported for 2D electrons in GaAs [20], LaAlO₃/SrTiO₃ heterojunctions [21], MoS₂ [22], and more recently bulk WSe₂ [23].

We turn now to the effective mass measurements. The SdH oscillation amplitude (ΔR_{xx}) is proportional to the Dingle factor, $\xi/\sinh \xi$, where $\xi = 2\pi^2 k_B T/\hbar\omega_c$, and $\omega_c = eB/m^*$ is the cyclotron frequency [24,25]; \hbar is the reduced Planck constant, and k_B is Boltzmann constant. Figure 4(a) shows the R_{xx} vs B data measured in monolayer WSe₂ at $p = 7.9 \times 10^{12}$ cm⁻², and at temperatures ranging between $T = 1.6$ and 7.0 K. Figure 4(b) presents the FT associated with Fig. 4(a) data. Data similar to Figs. 4(a) and 4(b) were acquired for bilayer WSe₂. We use the following procedure to extract m^* , which can be applied to both a single subband (e.g., monolayer WSe₂) or a multisubband 2D system (e.g., bilayer WSe₂). At a fixed temperature, we first obtain the FT of R_{xx} vs B^{-1} data as discussed in Fig. 2. We then apply a bandpass filter centered at f , or f' for the case of bilayer

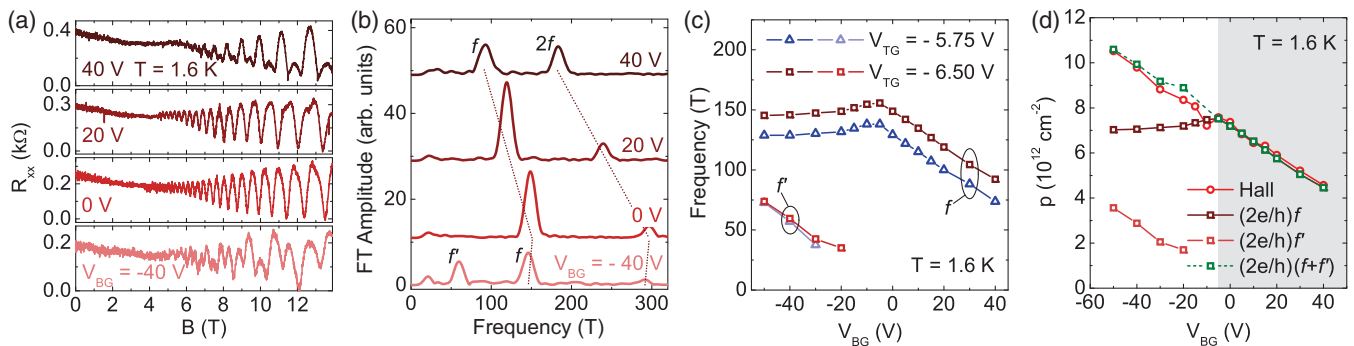


FIG. 3. (a) Bilayer WSe₂ R_{xx} vs B measured at various V_{BG} values, $V_{\text{TG}} = -6.5$ V, and $T = 1.6$ K. (b) FT amplitude vs frequency of panel (a) R_{xx} vs B^{-1} data; the traces are shifted for clarity. At negative V_{BG} an additional peak (f') emerges, and concomitantly f no longer increases with V_{BG} . The dashed lines are a guide to the eye. (c) f and f' vs V_{BG} in bilayer WSe₂ at $V_{\text{TG}} = -5.75$ V (triangles), $V_{\text{TG}} = -6.50$ V (rectangles). (d) p vs V_{BG} of bilayer WSe₂ measured at $V_{\text{TG}} = -6.5$ V. The dark (light) red squares mark the top (bottom) layer hole density. The shaded area marks the bottom layer depopulation.

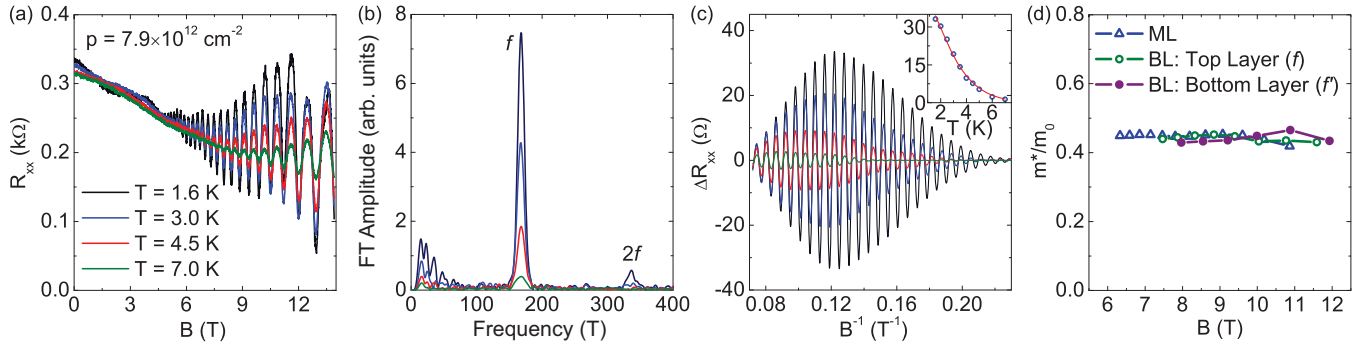


FIG. 4. (a) R_{xx} vs B in monolayer measured at different T values. (b) FT amplitude vs frequency corresponding to panel (a) R_{xx} vs B^{-1} data. (c) ΔR_{xx} vs B^{-1} calculated from the inverse FT of panel (b) data, using a bandpass filter to isolate the peak f . Inset: ΔR_{xx} vs T measured at $B = 7.81$ T (symbols), along with the Dingle factor fit (red line). (d) m^*/m_0 vs B in monolayer (ML), and bilayer (BL) WSe_2 . The bilayer data include values for both peaks (layers).

WSe_2 , and perform an inverse FT. Figure 4(c) shows ΔR_{xx} vs B^{-1} at different T values, obtained via the inverse FT from Fig. 4(b) data. At a fixed B field, the ΔR_{xx} vs T data of Fig. 4(c) are fitted to the Dingle factor to obtain m^* [Fig. 4(c) inset]. Figure 4(d) summarizes the extracted m^* values vs B for both mono- and bilayer WSe_2 . In monolayer, and also in either subband of the bilayer WSe_2 $m^* = 0.45m_0$, independent of the B field. The reported theoretical m^*/m_0 values for the upper valence band in monolayer WSe_2 include 0.33 [6], 0.34 [26], 0.36 [27,28], 0.43 [29], and 0.46 [30].

Last, we expand on the observed QHSs sequence. The valence band LLs cyclotron energies are $E_n = -n\hbar\omega_c$; n is the LL index. The LL degeneracy is 1 for $n = 0$, and 2 for $n > 0$, leading to expected QHSs at odd filling factors [6,7]. The experimental data show a twofold LL degeneracy, but the QHSs occur at predominantly even fillings. This can be explained by considering the LL valley and spin Zeeman energy $E_{\tau s} = g_v\tau\mu_B B + g_e s\mu_B B$, where μ_B is the Bohr magneton, $\tau = \pm 1$ corresponds to the K and K' valleys, $s = \pm 1/2$ to spin-up and spin-down states, and g_v and $g_e = 2$ are the valley and spin g factors, respectively. The τs product is the same for all the upper valence band LL states, e.g., $\tau s = 1/2$. If the ratio between the Zeeman and cyclotron LL splitting of $(1 + g_v)m^*/m_0$ is close to an integer, the QHSs revert to an even filling factor sequence at low B fields, and a full lifting of the LL degeneracy at high B fields [31]. Theoretically, $g_v = 2 + \alpha$, where the first term stems from d -orbital magnetic moment, and the second is associated with the valley Berry phase [32]. The measured m^* combined with the theoretical expression for $\alpha = m_0/m^*$ [32] yields a ratio of Zeeman to cyclotron energy of 2.3. However, this result should only be regarded as an estimate as the value and sign of g_v are yet to be established. Recent magneto-optical studies in monolayer WSe_2 [33–35] confirm the d -orbital contribution to the valley g factor, although the reported g_v values differ, and individual LLs were not resolved.

Resolving individual layer densities in bilayer WSe_2 indicates that the layers are weakly coupled, which contrasts the more familiar case of Bernal stacked bilayer graphene, where the strong van der Waals interlayer coupling (~ 0.4 eV) significantly alters the energy momentum dispersion compared to monolayer graphene. Calculated values of the interlayer coupling in bilayer WSe_2 range from 60 meV [29] to 67 meV [36]. We can estimate an upper bound of the interlayer coupling for the WSe_2 samples examined here. The minimum layer density difference of $3.5 \times 10^{12} \text{ cm}^{-2}$ determined from Fig. 3(d) data, combined with a density of states $m^*/\pi\hbar^2 = 1.87 \times 10^{14} \text{ cm}^{-2} \text{ eV}^{-1}$ yields a subband separation of 19 meV.

To summarize, we present a magnetotransport study of mono- and bilayer WSe_2 . The data reveal SdH oscillations and QHSs in both mono- and bilayer samples that occur primarily at even filling factors. The FT analysis evinces two subbands in bilayer WSe_2 , located in the top and bottom layers, and negative compressibility of carriers in individual WSe_2 layers. We determine a hole effective mass of $0.45m_0$ in both mono- and bilayer WSe_2 .

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B. F. and H. C. P. M. contributed equally to this study.

* etutuc@mer.utexas.edu

- [1] D. Xiao, G.-B. Liu, W. Feng, X. Xu, and W. Yao, *Phys. Rev. Lett.* **108**, 196802 (2012).
- [2] K. F. Mak, K. He, J. Shan, and T. F. Heinz, *Nat. Nanotechnol.* **7**, 494 (2012).
- [3] A. M. Jones *et al.*, *Nat. Nanotechnol.* **8**, 634 (2013).

- [4] Y. Li *et al.*, *Phys. Rev. Lett.* **113**, 266804 (2014).
- [5] A. M. Jones, H. Yu, J. S. Ross, P. Klement, N. J. Ghimire, J. Yan, D. G. Mandrus, W. Yao, and X. Xu, *Nat. Phys.* **10**, 130 (2014).
- [6] X. Li, F. Zhang, and Q. Niu, *Phys. Rev. Lett.* **110**, 066803 (2013).
- [7] F. Rose, M. O. Goerbig, and F. Piéchon, *Phys. Rev. B* **88**, 125438 (2013).
- [8] K. S. Novoselov, A. K. Geim, S. V. Morozov, D. Jiang, Y. Zhang, S. V. Dubonos, I. V. Grigorieva, and A. A. Firsov, *Science* **306**, 666 (2004).
- [9] Y. Zhang, Y.-W. Tan, H. L. Stormer, and P. Kim, *Nature (London)* **438**, 201 (2005).
- [10] X. Cui *et al.*, *Nat. Nanotechnol.* **10**, 534 (2015).
- [11] H. C. P. Movva, A. Rai, S. Kang, K. Kim, B. Fallahazad, T. Taniguchi, K. Watanabe, E. Tutuc, and S. K. Banerjee, *ACS Nano* **9**, 10402 (2015).
- [12] C. R. Dean *et al.*, *Nat. Nanotechnol.* **5**, 722 (2010).
- [13] H. Terrones *et al.*, *Sci. Rep.* **4** (2014).
- [14] K. Kim, S. Larentis, B. Fallahazad, K. Lee, J. Xue, D. C. Dillen, C. M. Corbet, and E. Tutuc, *ACS Nano* **9**, 4527 (2015).
- [15] W. Zhao, Z. Ghorannevis, L. Chu, M. Toh, C. Kloc, P.-H. Tan, and G. Eda, *ACS Nano* **7**, 791 (2013).
- [16] G.-B. Liu, D. Xiao, Y. Yao, X. Xu, and W. Yao, *Chem. Soc. Rev.* **44**, 2643 (2015).
- [17] A. B. Fowler, F. F. Fang, W. E. Howard, and P. J. Stiles, *Phys. Rev. Lett.* **16**, 901 (1966).
- [18] Y. P. Shkolnikov, E. P. De Poortere, E. Tutuc, and M. Shayegan, *Phys. Rev. Lett.* **89**, 226805 (2002).
- [19] Y. Katayama, D. C. Tsui, H. C. Manoharan, S. Parihar, and M. Shayegan, *Phys. Rev. B* **52**, 14817 (1995).
- [20] J. P. Eisenstein, L. N. Pfeiffer, and K. W. West, *Phys. Rev. B* **50**, 1760 (1994).
- [21] L. Li, C. Richter, S. Paetel, T. Kopp, J. Mannhart, and R. C. Ashoori, *Science* **332**, 825 (2011).
- [22] S. Larentis, J. R. Tolsma, B. Fallahazad, D. C. Dillen, K. Kim, A. H. MacDonald, and E. Tutuc, *Nano Lett.* **14**, 2039 (2014).
- [23] J. M. Riley *et al.*, *Nat. Nanotechnol.* **10**, 1043 (2015).
- [24] R. B. Dingle, *Proc. R. Soc. A* **211**, 517 (1952).
- [25] E. N. Adams and T. D. Holstein, *J. Phys. Chem. Solids* **10**, 254 (1959).
- [26] H. Shi, H. Pan, Y.-W. Zhang, and B. I. Yakobson, *Phys. Rev. B* **87**, 155304 (2013).
- [27] A. Kormányos, G. Burkard, M. Gmitra, J. Fabian, V. Zólyomi, N. D. Drummond, and V. Fáłko, *2D Mater.* **2**, 022001 (2015).
- [28] N. Zibouche, P. Philipsen, T. Heine, and A. Kuc, *Phys. Chem. Chem. Phys.* **16**, 11251 (2014).
- [29] S. Fang, R. Kuate Defo, S. N. Shirodkar, S. Lieu, G. A. Tritsarlis, and E. Kaxiras, *Phys. Rev. B* **92**, 205108 (2015).
- [30] J. Chang, L. F. Register, and S. K. Banerjee, *J. Appl. Phys.* **115**, 084506 (2014).
- [31] R.-L. Chu, X. Li, S. Wu, Q. Niu, W. Yao, X. Xu, and C. Zhang, *Phys. Rev. B* **90**, 045427 (2014).
- [32] D. Xiao, W. Yao, and Q. Niu, *Phys. Rev. Lett.* **99**, 236809 (2007).
- [33] A. Srivastava, M. Sidler, A. V. Allain, D. S. Lembke, A. Kis, and A. Imamoglu, *Nat. Phys.* **11**, 141 (2015).
- [34] G. Aivazian, Z. Gong, A. M. Jones, R.-L. Chu, J. Yan, D. G. Mandrus, C. Zhang, D. Cobden, W. Yao, and X. Xu, *Nat. Phys.* **11**, 148 (2015).
- [35] A. A. Mitioglu, P. Plochocka, A. G. del Aguila, P. C. M. Christianen, G. Deligeorgis, S. Anghel, L. Kulyuk, and D. K. Maude, *Nano Lett.* **15**, 4387 (2015).
- [36] Z. Gong, G.-B. Liu, H. Yu, D. Xiao, X. Cui, X. Xu, and W. Yao, *Nat. Commun.* **4**, 2053 (2013).